

## Supplementary information

### Superior energy density through tailored dopant strategies in multilayer ceramic capacitors

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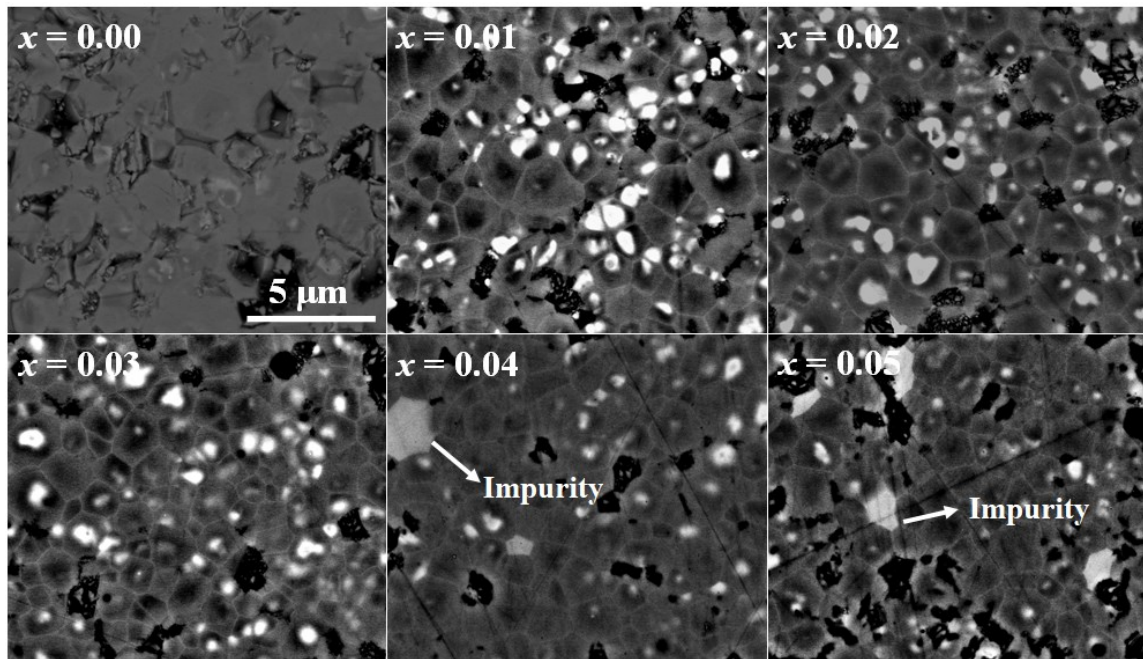


Figure S1 BSE images acquired from polished surfaces of BF-ST-BMN- $x$ Nb ( $x = 0, 0.01, 0.02, 0.03, 0.04$  and  $0.05$ ) ceramics.

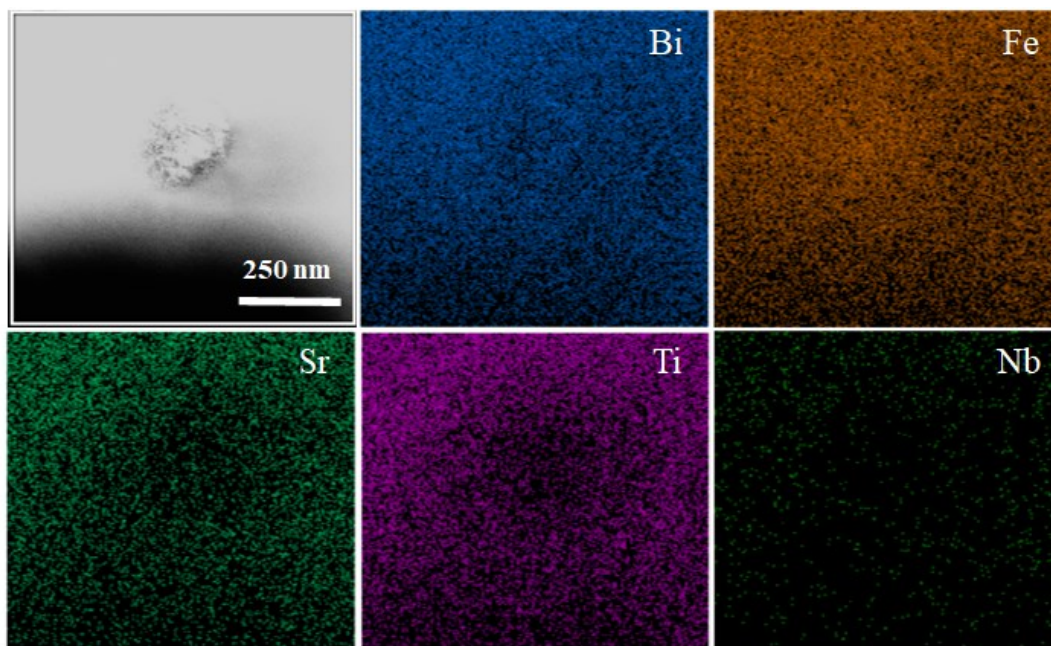


Figure S2 EDS elemental maps obtained from BF-ST-BMN-0.03Nb.

Table 1 Atomic percentage (excl. O) calculated from EDS spectra obtained from different phases presented in BF-ST-BMN-xNb ( $x = 0.05$ ).

Elements	Bright core	Dark core
Bi	37.1	28.9
Fe	32.4	23.8
Sr	12.8	22.4
Ti	13.8	20.6
Mg	2.0	2.2
Nb	2.0	2.0

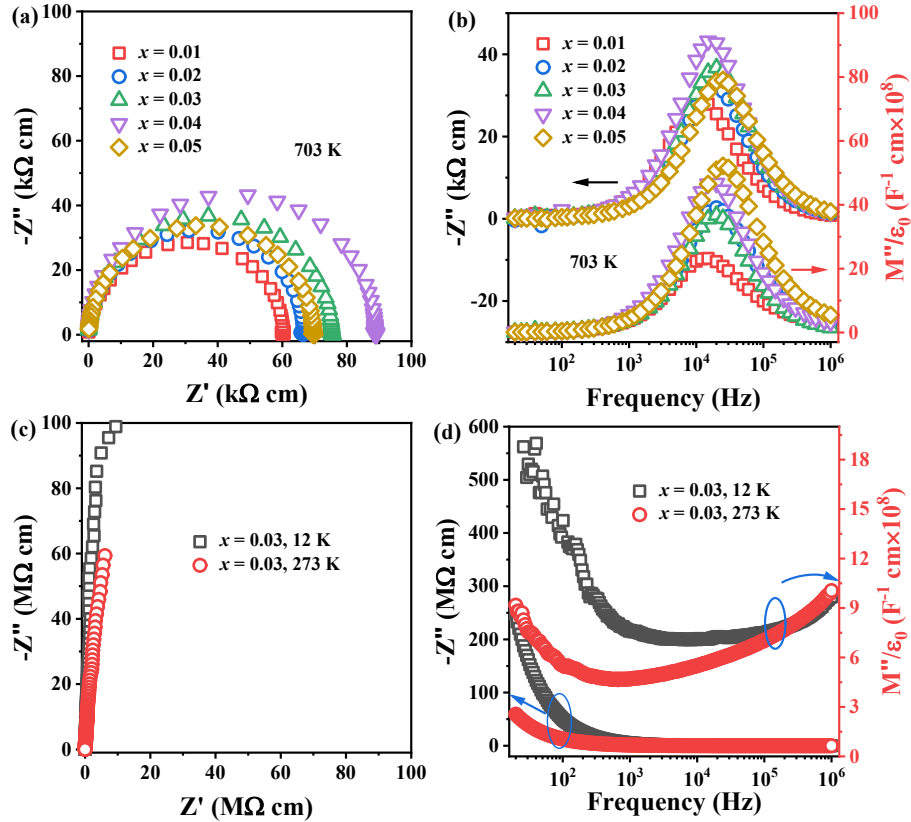


Figure S3 (a)  $Z^*$  plots and (b)  $Z''$  and  $M''$  spectroscopic plots at 703 K of BF-ST-BMN-xNb ( $x = 0.01, 0.02, 0.03, 0.04$  and  $0.05$ ) ceramics; (c)  $Z^*$  plots and (d)  $Z''$  and  $M''$  spectroscopic plots of  $x = 0.03$  at 12 and 273 K.

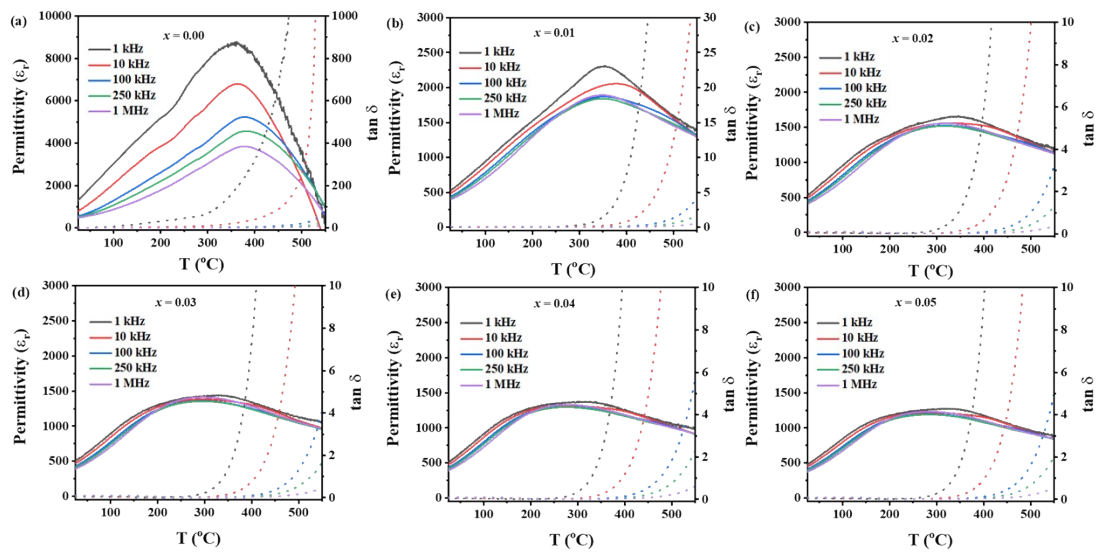


Figure S4 The temperature- and frequency-dependent dielectric permittivity ( $\epsilon_r$  vs  $T$ ) and loss ( $\tan \delta$  vs  $T$ ) data for BF-ST-BMN- $x$ Nb,  $x =$  (a) 0, (b) 0.01, (c) 0.02, (d) 0.03, (e) 0.04 and (f) 0.05.

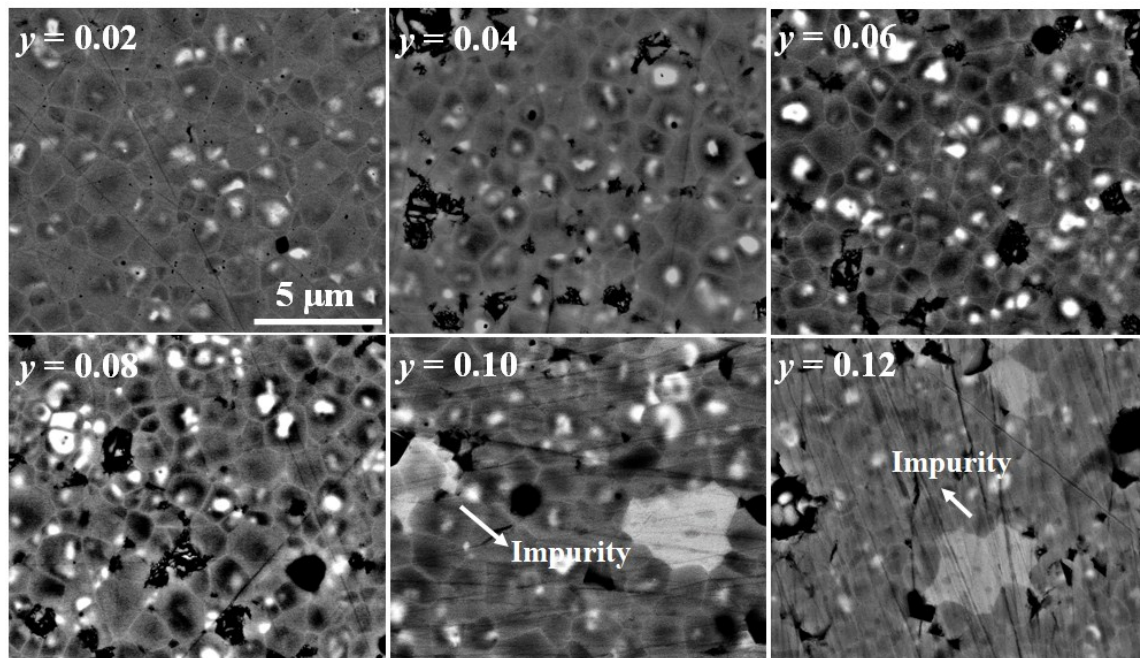


Figure S5 BSE images acquired from polished surfaces of BF-ST-Nb- $y$ BMN ( $y = 0.02, 0.04, 0.06, 0.08, 0.10$  and  $0.12$ ).

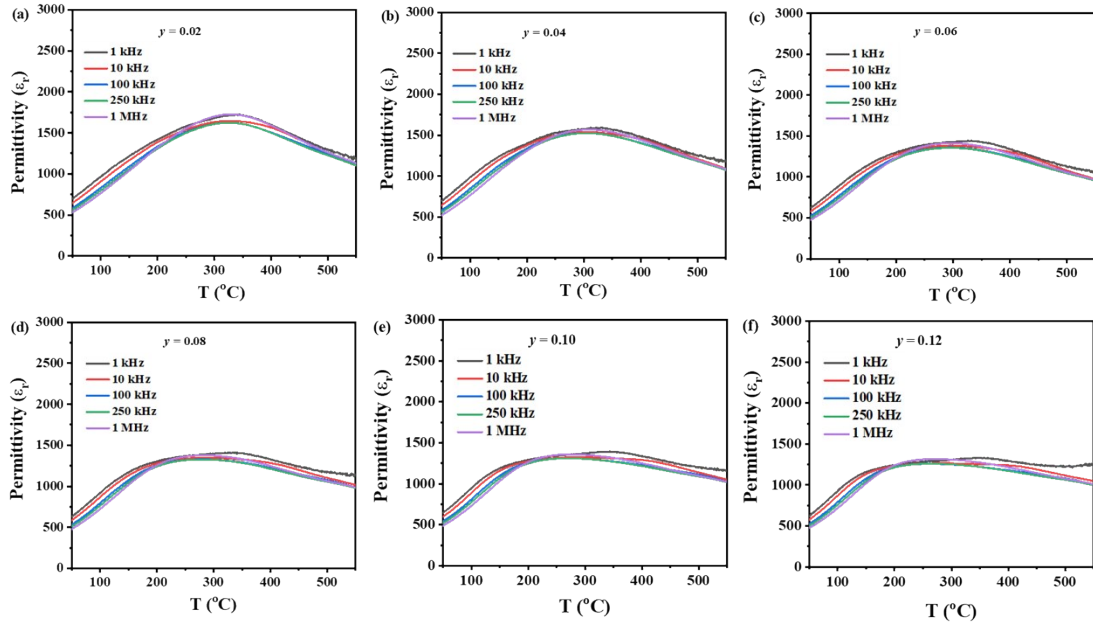


Figure S6 The temperature- and frequency-dependent dielectric permittivity ( $\epsilon_r$  vs  $T$ ) of BF-ST-Nb- $y$ BMN ( $y = 0.02, 0.04, 0.06, 0.08, 0.10$  and  $0.12$ ).

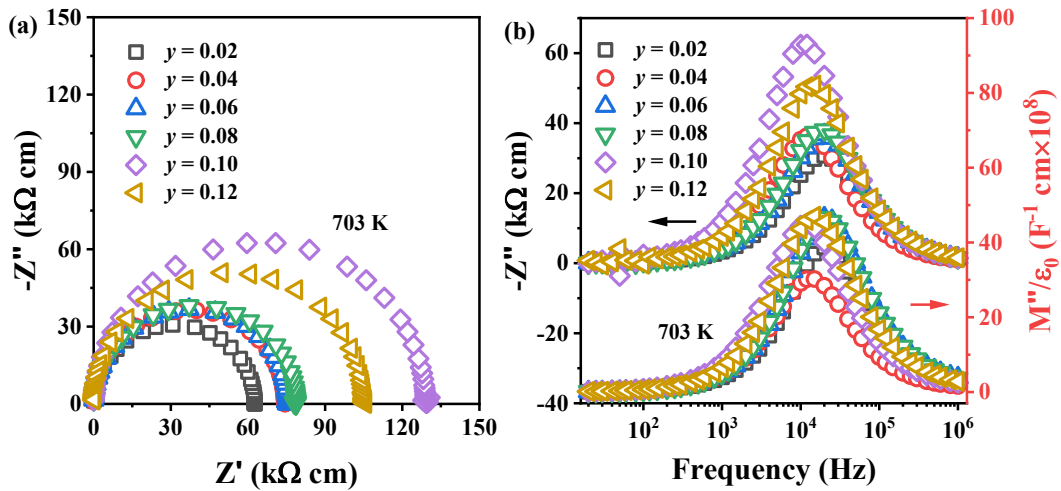


Figure S7 (a)  $Z^*$  plots and (b)  $Z''$  and  $M''$  spectroscopic plots at 703 K of BF-ST-Nb- $y$ BMN ( $y = 0.02, 0.04, 0.06, 0.08, 0.10$  and  $0.12$ ).

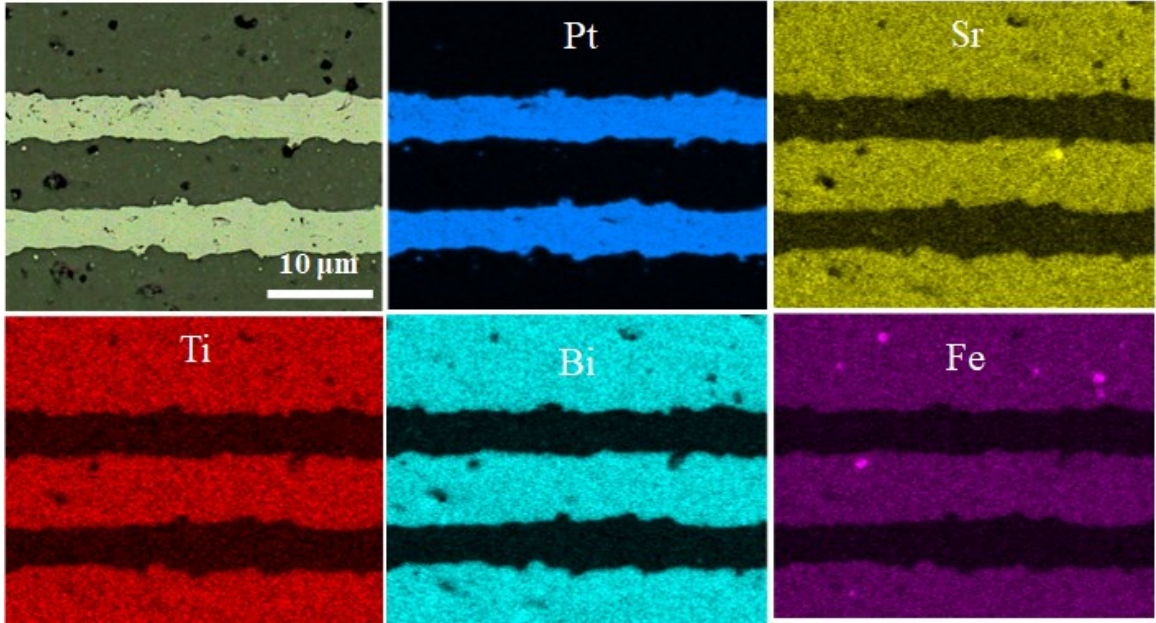


Figure S8 SEM image and corresponding EDS elemental maps obtained from the cross section of BF-ST-Nb-0.1BMN multilayer.